

# **Opti**MOS<sup>™</sup>2 Power-Transistor

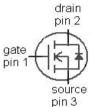
#### **Features**

- N-channel, normal level
- Excellent gate charge x R<sub>DS(on)</sub> product (FOM)
- Very low on-resistance R<sub>DS(on)</sub>
- 175 °C operating temperature
- · Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target application
- Ideal for high-frequency switching and synchronous rectification
- Halogen-free according to IEC61249-2-21

# **Product Summary**

$V_{ m DS}$	100	٧
R <sub>DS(on).max (TO252)</sub>	25	mΩ
I <sub>D</sub>	35	А







Туре	IPB26CN10N G	IPD25CN10N G	IPI26CN10N G	IPP26CN10N G
	1 2 (tab)	1 2 (tab)	123	123
Package	PG-TO263-3	PG-TO252-3	PG-TO262-3	PG-TO220-3
Marking	26CN10N	25CN10N	26CN10N	26CN10N

# **Maximum ratings,** at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C	35	А
		T <sub>C</sub> =100 °C	25	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	140	
Avalanche energy, single pulse	E <sub>AS</sub>	$I_{D}$ =35 A, $R_{GS}$ =25 Ω	65	mJ
Reverse diode d $v$ /d $t$	dv/dt	$I_{\rm D}\!\!=\!\!35~{\rm A},~V_{\rm DS}\!\!=\!\!80~{\rm V},$ ${\rm d}i/{\rm d}t\!\!=\!\!100~{\rm A/\mu s},$ $T_{\rm j,max}\!\!=\!\!175~{\rm ^{\circ}C}$	6	kV/μs
Gate source voltage <sup>3)</sup>	$V_{GS}$		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	71	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

<sup>1)</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>2)</sup> see figure 3

<sup>&</sup>lt;sup>3)</sup> T<sub>imax</sub>=150°C and duty cycle D=0.01 for Vgs<-5V



# IPB26CN10N G IPD25CN10N G IPI26CN10N G IPP26CN10N G

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics	,					
Thermal resistance, junction - case	$R_{thJC}$		-	-	2.1	K/W
Thermal resistance, junction -	$R_{thJA}$	minimal footprint	-	-	62	]
ambient (TO220, TO262, TO263)		6 cm2 cooling area <sup>4)</sup>	-	-	40	1
Thermal resistance, junction -		minimal footprint	-	-	75	1
ambient (TO252, TO251)		6 cm2 cooling area <sup>4)</sup>	-	-	50	1

# **Electrical characteristics**, at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	100	ı	ı	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 39  \mu {\rm A}$	2	3	4	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS} = 80 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.1	1	μA
		V <sub>DS</sub> =80 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V	-	1	100	nA
Drain-source on-state resistance	$R_{ ext{DS(on)}}$	V <sub>GS</sub> =10 V, I <sub>D</sub> =35 A, (TO252)	1	19	25	mΩ
		V <sub>GS</sub> =10 V, I <sub>D</sub> =35 A, (TO251)	-	19	25	
		V <sub>GS</sub> =10 V, I <sub>D</sub> =35 A, (TO263)	-	20	26	
		V <sub>GS</sub> =10 V, I <sub>D</sub> =35 A, (TO220, TO262)	-	20	26	
Gate resistance	$R_{G}$		-	1.1	-	Ω
Transconductance	$g_{fs}$	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 35~{\rm A}$	19	38	-	s

 $<sup>^{4)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^{2}$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



# IPB26CN10N G IPD25CN10N G IPI26CN10N G IPP26CN10N G

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	1560	2070	pF
Output capacitance	Coss	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =50 V, $f$ =1 MHz	-	232	309	
Reverse transfer capacitance	C <sub>rss</sub>	]	-	16	24	
Turn-on delay time	t <sub>d(on)</sub>		-	10	15	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =10 V,	-	4	6	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D} = 35  \text{A},  R_{\rm G,ext} = 1.6  \Omega$	-	13	19	
Fall time	$t_{\mathrm{f}}$		-	3	4	
Gate Charge Characteristics <sup>5)</sup>	1			Г	Г	
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =50 V, I <sub>D</sub> =35 A, V <sub>GS</sub> =0 to 10 V	-	9	12	nC
Gate to drain charge	Q <sub>gd</sub>		-	6	8	
Switching charge	Q <sub>sw</sub>		-	10	14	
Gate charge total	Qg		-	23	31	
Gate plateau voltage	$V_{\rm plateau}$		-	5.6	-	V
Output charge	Q <sub>oss</sub>	V <sub>DD</sub> =50 V, V <sub>GS</sub> =0 V	-	24	32	nC
Reverse Diode						
Diode continous forward current	Is	T _25 °C	-	-	35	А
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	140	1
Diode forward voltage	$V_{\mathrm{SD}}$	V <sub>GS</sub> =0 V, I <sub>F</sub> =35 A, T <sub>j</sub> =25 °C	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =50 V, I <sub>F</sub> =I <sub>S</sub> ,	-	85		ns
Reverse recovery charge	Q <sub>rr</sub>	di <sub>F</sub> /dt=100 A/µs	-	165	-	nC

<sup>&</sup>lt;sup>5)</sup> See figure 16 for gate charge parameter definition

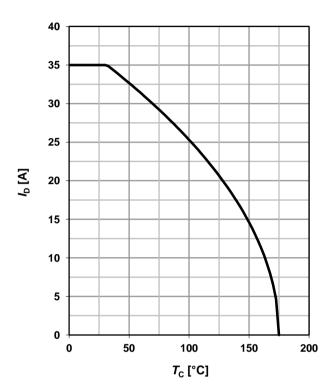


# 1 Power dissipation

# $P_{\text{tot}} = f(T_{\text{C}})$

# 80 70 60 50 $P_{\text{tot}}$ [W] 40 30 20 10 0 0 50 100 150 200 *T*<sub>C</sub> [°C]

#### 2 Drain current



# 3 Safe operating area

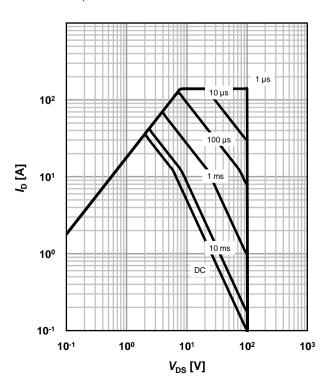
 $I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$ 

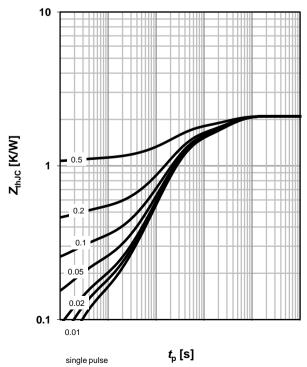
parameter:  $t_p$ 

# 4 Max. transient thermal impedance

 $Z_{\text{thJC}}$ =f( $t_{p}$ )

parameter:  $D=t_p/T$ 



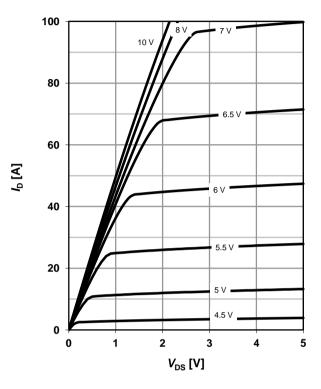




# 5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$ 

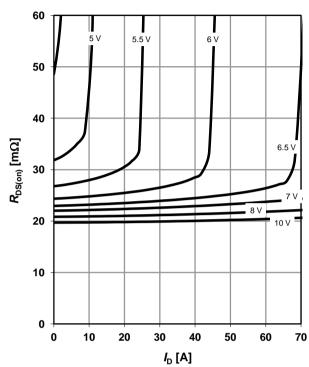
parameter: V<sub>GS</sub>



# 6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 °C$ 

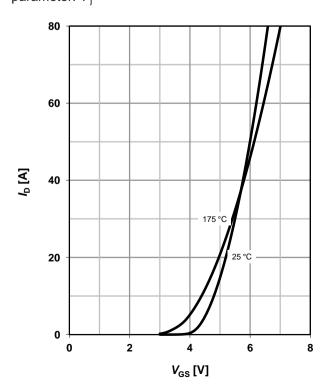
parameter: V<sub>GS</sub>



# 7 Typ. transfer characteristics

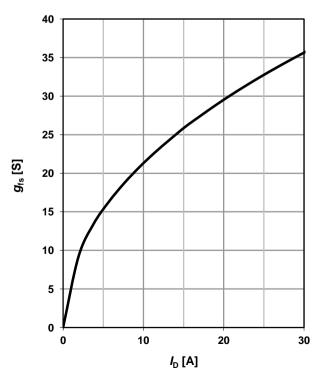
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$ 

parameter: T<sub>i</sub>



# 8 Typ. forward transconductance

 $g_{fs}$ =f( $I_D$ );  $T_j$ =25 °C





#### 9 Drain-source on-state resistance

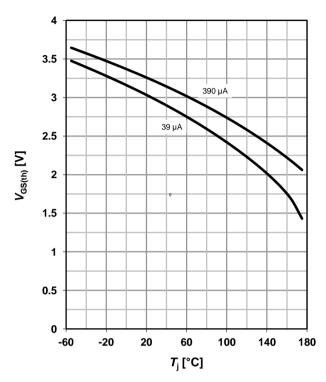
 $R_{DS(on)} = f(T_i); I_D = 35 \text{ A}; V_{GS} = 10 \text{ V}$ 

# 

# 10 Typ. gate threshold voltage

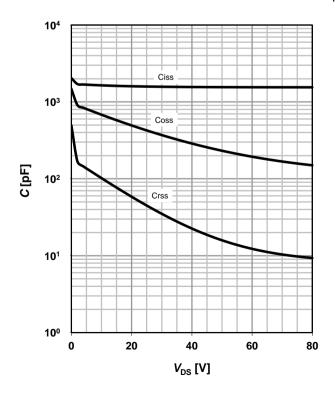
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>



# 11 Typ. capacitances

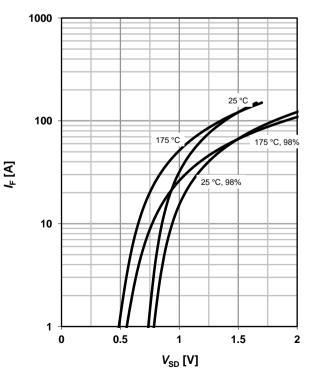
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 



#### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter: T<sub>i</sub>

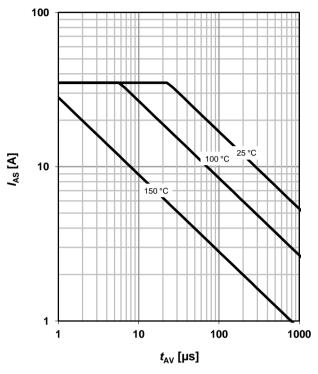




#### 13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$ 

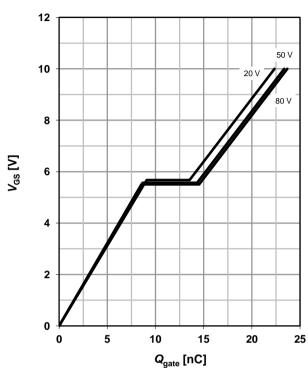
parameter:  $T_{j(start)}$ 



# 14 Typ. gate charge

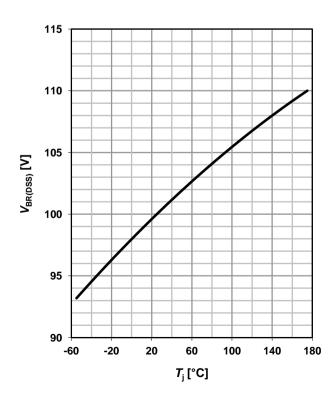
 $V_{GS}$ =f( $Q_{gate}$ );  $I_D$ =35 A pulsed

parameter:  $V_{\rm DD}$ 

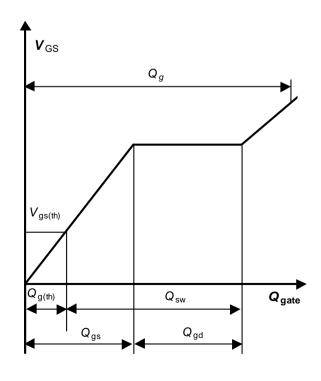


# 15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$ 

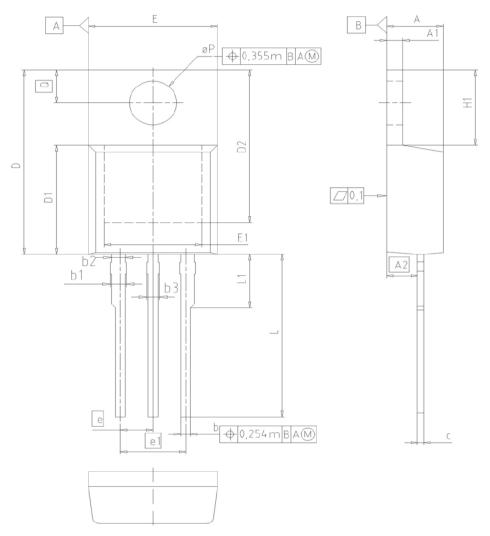


#### 16 Gate charge waveforms

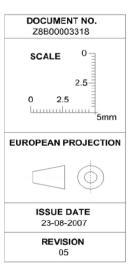




#### PG-TO220-3: Outline

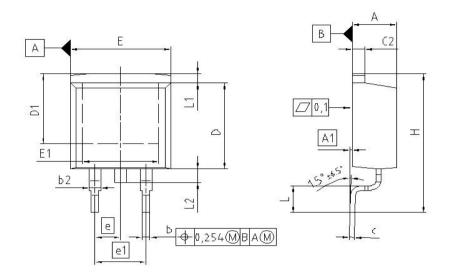


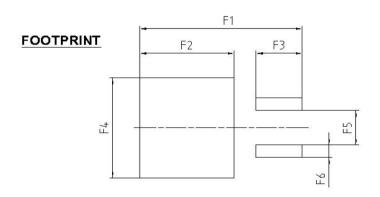
DIM	MILLIMETERS		INCI	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.	2.54		100
e1	5.	08	0.2	200
N		3		3
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118
		2.00	5.10E	5.110



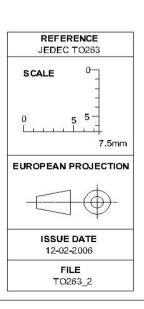


# PG-TO-263 (D2-Pak)



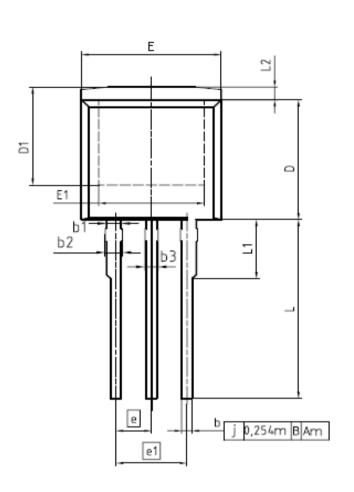


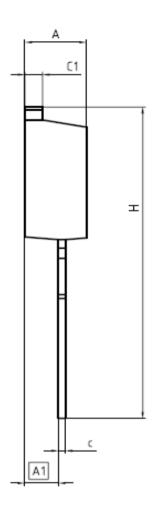
DIM	MILLIM	ETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	0.000	0.254	0.000	0.010
b	0.650	0.850	0.026	0.033
b2	0.950	1.321	0.037	0.052
C	0.330	0.650	0.013	0.026
c2	0.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	7.100	-	0.280	-
E	9.800	10.312	0.386	0.406
E1	6.500		0.256	
e	2.540		0.100	
e1	5.0	80	0.2	200
N	2	2	2	2
Н	14.605	15.875	0.575	0.625
L	2.200	3.000	0.087	0.118
L1	-	1.600	-	0.063
L2	1.000	1.778	0.039	0.070
F1	16.050	16.250	0.632	0.640
F2	9.300	9.500	0.366	0.374
F3	4.500	4.700	0.177	0.185
F4	10.700	10.900	0.421	0.429
F5	3.630	3.830	0.143	0.151
F6	1.100	1.300	0.043	0.051



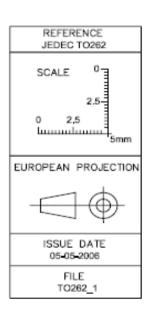


# PG-TO262-3-1 (I<sup>2</sup>PAK)





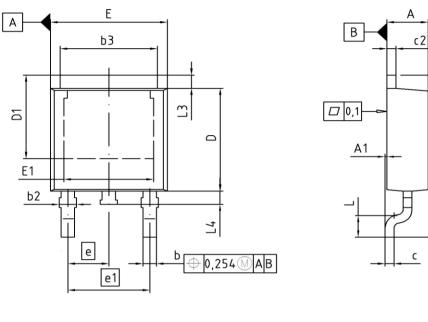
DIM	MILLIME	ETERS	INCH	IES
DIM	MIN	MAX	MIN	MAX
Α	4,300	4,572	0,169	0,180
A1	2.150	2.718	0.085	0.107
Ь	0.650	0.864	0.026	0.034
b1	0,950	1,093	0,037	0,043
b2	0.950	1,400	0.037	0.055
ь3	0.650	1.118	0.026	0.044
С	0,330	0,600	0,013	0,024
c1	1.170	1,400	0.046	0.055
D	8,509	9.450	0.335	0,372
D1	6,900	-	0,272	
E	9.700	10.363	0.382	0.408
E1	6,500	8,600	0,256	0,339
e	2,5	40	0,1	00
e1	5.0	80	0.2	200
N	3	3		3
L	13,000	14,000	0,512	0,551
L1	-	4.800	-	0.189
L2	-	1,727		0,068

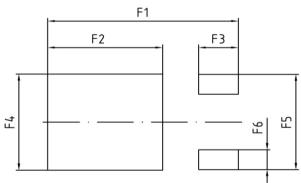


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# PG-TO252-3: Outline





DIM	MILLIM	ETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	2.16	2.41	0.085	0.095	
A1	0.00	0.15	0.000	0.006	
b	0.64	0.89	0.025	0.035	
b2	0.65	1.15	0.026	0.045	
ь3	5.00	5.50	0.197	0.217	
С	0.46	0.60	0.018	0.024	
c2	0.46	0.98	0.018	0.039	
D	5.97	6.22	0.235	0.245	
D1	5.02	5.84	0.198	0.230	
E	6.40	6.73	0.252	0.265	
E1	4.70	5.21	0.185	0.205	
е	2	.29	0.090		
e1	4	.57	0.180		
N		3	;	3	
Н	9.40	10.48	0.370	0.413	
L	1.18	1.70	0.046	0.067	
L3	0.90	1.25	0.035	0.049	
L4	0.51	1.00	0.020	0.039	
F1	10.50	10.70	0.413	0.421	
F2	6.30	6.50	0.248	0.256	
F3	2.10	2.30	0.083	0.091	
F4	5.70	5.90	0.224	0.232	
F5	5.66	5.86	0.223	0.231	
F6	1.10	1.30	0.043	0.051	

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